Bi-Quinary Counter

S1

10

D1

D2 Q

C2 Q

C2 7

V_{CC1}

Q3

Q3

Q2

S3

S2

C2

 V_{EE}

1

2

3

4

5

6

7

8

Q1

13

G

The MC10138 is a four bit counter capable of divide by two, five, or ten functions. It is composed of four set-reset master-slave flip-flops. Clock inputs trigger on the positive going edge of the clock pulse.

Set or reset input override the clock, allowing asynchronous "set" or "clear." Individual set and common reset inputs are provided, as well as complementary outputs for the first and fourth bits.

- $P_D = 370 \text{ mW typ/pkg}$ (No Load)
- $f_{tog} = 150 \text{ MHz typ}$

S0

11

D1

C1

R

12

Clock

9

Reset

• t_r , $t_f = 2.5$ ns typ (20%-80%)

Q0

15

Q

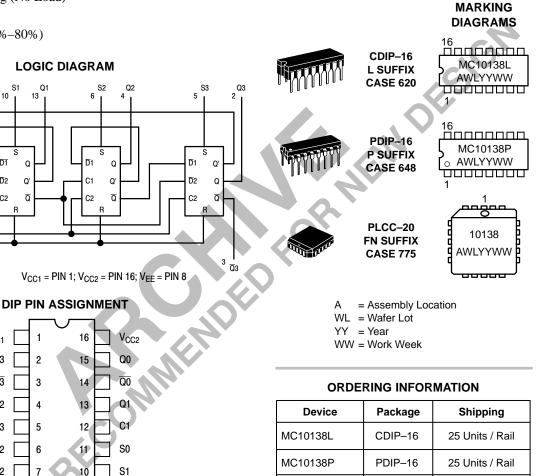
Q

14 . Q0



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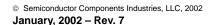
MC10138FN

PLCC-20

Pin assignment is for Dual-in-Line Package. For PLCC pin assignment, see the Pin Conversion Tables on page 18 of the ON Semiconductor MECL Data Book (DL122/D).

9

RESET



46 Units / Rail

Downloaded from Elcodis.com electronic components distributor

JEVIC

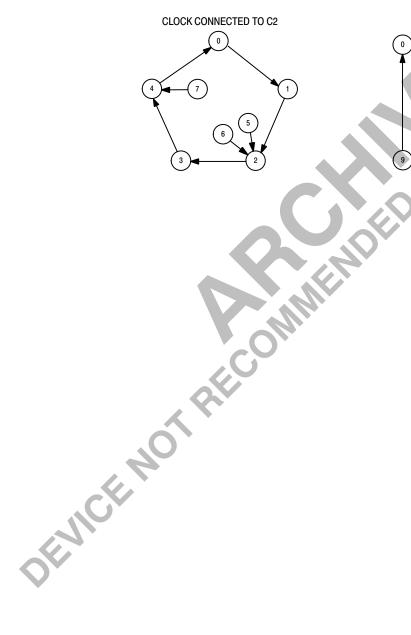
COUNTER TRUTH TABLES

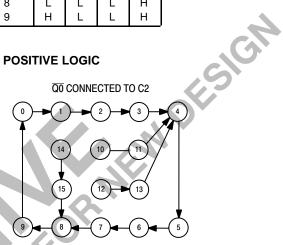
BI–QUINARY (Clock connected to C2 BCD (Clock connected to C1

and $\overline{Q3}$ connected to C1)								
COUNT	OUNT Q1 Q2 Q3 Q0							
0	L	L	L	L				
1	н	L	L	L				
2	L	Н	L	L				
3	Н	Н	L	L				
4	L	L	Н	L				
5	L	L	L	Н				
6	н	L	L	Н				
7	L	Н	L	Н				
8	Н	Н	L	Н				
9	L	L	Н	Н				

and Q0 connected to C2)								
COUNT	Q0	Q1	Q2	Q3				
0	L	L	L	L				
1	н	L	L	L				
2	L	н	L	L				
3	н	Н	L	L				
4	L	L	Н	L				
5	н	L	н	L				
6	L	н	н	L				
7	Н	Н	Н	L				
8	L	L	L	Н				

COUNTER STATE DIAGRAM — POSITIVE LOGIC





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ELECTRICAL CHARACTERISTICS

			Test Limits							
		Pin Under	-30	D∘C		+25°C		+8	5°C	
Characteristic	Symbol	Test	Min	Max	Min	Тур	Max	Min	Max	Unit
Power Supply Drain Cur- rent	Ι _Ε	8		97		70	88		97	mAdc
Input Current	l _{inH}	12 5,6,10,11 7 9		350 390 460 650			220 245 290 410		220 245 290	μAdc
	I _{inL}	All	0.5		0.5			0.3		μAdc
Output Voltage Logic 1	V _{OH}	3,14 (3.) 2,4,13,15 (2.)	-1.060 -1.060	-0.890 -0.890	-0.960 -0.960		-0.810 -0.810	-0.890 -0.890	-0.700 -0.700	Vdc
Output Voltage Logic 0	V _{OL}	3,14 (2.) 2,4,13,15 (3.)	-1.890 -1.890	-1.675 -1.675	-1.850 -1.850		-1.650 -1.650	-1.825 -1.825	-1.615 -1.615	Vdc
Threshold Voltage Logic 1	V _{OHA}	2,4,13,15 (2.) 3,14 (3.) 13,15 (2.)	-1.080 -1.080 -1.080		-0.980 -0.980 -0.980			-0.910 -0.910 -0.910	S.	Vdc
Threshold Voltage Logic 0	V _{OLA}	2,4,13,15 (3.) 3,14 (2.) 13,15 (3.)		-1.655 -1.655 -1.655			-1.630 -1.630 -1.630	2	-1.595 -1.595 -1.595	Vdc
Switching Times (50Ω Load)							S.			ns
Propagation Clock Delays Delay	t ₁₂₊₁₅₊ t ₁₂₊₁₄₊ t ₇₊₁₃₊ t ₇₊₂₊ t ₇₊₂₊ t ₇₊₃₊	15 14 13 4 2 3	1.4 1.4 1.4 1.4 1.4 1.4	5.0 5.0 5.2 5.2 5.2 5.2 5.2	1.5 1.5 1.5 1.5 1.5 1.5	3.5 3.5 3.5 3.5 3.5 3.5 3.5	4.8 4.8 5.0 5.0 5.0 5.0	1.5 1.5 1.5 1.5 1.5 1.5	5.3 5.3 5.5 5.5 5.5 5.5	
	t ₁₂₊₁₅₋ t ₁₂₊₁₄₋ t ₇₊₁₃₋ t ₇₊₄₋ t ₇₊₂₋ t ₇₊₃₋	15 14 13 4 2 3	1.4 1.4 1.4 1.4 1.4 1.4	5.0 5.0 5.2 5.2 5.2 5.2 5.2	1.5 1.5 1.5 1.5 1.5 1.5 1.5	3.5 3.5 3.5 3.5 3.5 3.5 3.5	4.8 4.8 5.0 5.0 5.0 5.0	1.5 1.5 1.5 1.5 1.5 1.5	5.3 5.3 5.5 5.5 5.5 5.5 5.5	
Set Delay	t ₁₁₊₁₅₊ t _{11+14–}	15 14	1.4 1.4	5.2 5.2	1.5 1.5		5.0 5.0	1.5 1.5	5.5 5.5	
Reset Delay	t ₉₊₁₄₊ t _{9+15–}	14 15	1.4 1.4	5.2 5.2	1.5 1.5		5.0 5.0	1.5 1.5	5.5 5.5	
Rise Time (20 to 80%)	t ₁₄₊ t ₁₅₊	14 15	1.1 1.1	4.7 4.7	1.1 1.1	2.5 2.5	4.5 4.5	1.1 1.1	5.0 5.0	
Fall Time (20 to 80%)	t ₁₄₋ t ₁₅₋	14 15	1.1 1.1	4.7 4.7	1.1 1.1	2.5 2.5	4.5 4.5	1.1 1.1	5.0 5.0	
Counting Frequency	f _{count}	2 15	125 125		125 125	150 150		125 125		MHz

Individually test each input; apply V_{ILmin} to pin under test.
Set all four flips by applying pulse.

2. Set all four flip-flops by applying pulse

3. Reset all four flip-flops by applying pulse

VILmin VILmin

VILmin

to pins 5, 6, 10, and 11 prior to applying test voltage indicated.

to pin 9 prior to applying test voltage indicated.

ELECTRICAL CHARACTERISTICS (continued)

OTE: Each MECL 10,000 series circuit has een designed to meet the dc specifications			TEST VOLTAGE VALUES (Volts)					
shown in the test table, after thermal equilibrium has been established. The circuit	@ Test Temperature -30°C		V _{IHmax}	V _{ILmin}	V _{IHAmin}	V _{ILAmax}	V _{EE}	
s in a test socket or mounted on a printed circuit board and transverse air flow greater			-0.890	-1.890	-1.205	-1.500	-5.2	
han 500 linear fpm is maintained. Outputs are erminated through a 50-ohm resistor to -2.0 volts. Test procedures are shown for only one		+25°C	-0.810	-1.850	-1.105	-1.475	-5.2	
gate. The other gates are tested in the same nanner.	+85°C		-0.700	-1.825	-1.035	-1.440	-5.2	
		Pin	TEST V	OLTAGE AP	PLIED TO P	INS LISTED	BELOW	
Characteristic	Symbol	Under Test	V _{IHmax}	V _{ILmin}	V _{IHAmin}	V _{ILAmax}	V _{EE}	(V _{CC} Gnd
Power Supply Drain Current	Ι _Ε	8	9				8	1, 16
Input Current	I _{inH}	12 5,6,10,11	12 5,6,10,11				8 8	1, 16 1, 16
		7 9	7 9				8 8	1, 16
·	I _{inL}	All		Note 1.			8	1, 16
Output Voltage Logic 1	V _{OH}	3,14 (3.) 2,4,13,15 (2.)	9 5,6,10,11				8 8	1, 16 1, 16
Output Voltage Logic 0	V _{OL}	3,14 (2.) 2,4,13,15 (3.)	5,6,10,11 9				8 8	1, 16 1, 16
Threshold Voltage Logic 1	V _{OHA}	2,4,13,15 (2.)			5,6,10,11		8	1, 16
		3,14 (3.) 13,15 (2.)			9 7,12		8 8	1, 16 1, 16
Threshold Voltage Logic 0	V _{OLA}	2,4,13,15 (3.)				5,6,10,11	8	1, 16
		3,14 (2.) 13,15 (3.)			6	9 7,12	8 8	1, 16 1, 16
Switching Times (50Ω Load)					Pulse In	Pulse Out	–3.2 V	+2.0
Propagation Delay Clock Delays	t ₁₂₊₁₅₊	15			12	15	8	1, 16
	t ₁₂₊₁₄₊ t ₇₊₁₃₊	14 13			12 7	14 13	8 8	1, 16 1, 16
	t ₇₊₁₃₊	4			7	4	8	1, 16
	t ₇₊₂₊	2			7	2	8	1, 16
	t ₇₊₃₊	3			7	3	8	1, 16
	t ₁₂₊₁₅₋	15			12	15	8	1, 16
	t ₁₂₊₁₅ -	14			12	14	8	1, 16
	t ₇₊₁₃₋	13			7	13	8	1, 16
	t ₇₊₄₋	4			7	4	8	1, 16
	t ₇₊₂₋	2			7	2	8	1, 16
	t ₇₊₃₋	3			7	3	8	1, 16
Set Delay	t ₁₁₊₁₅₊ t ₁₁₊₁₄₋	15 14			11 11	15 14	8 8	1, 16 1, 16
Reset Delay	t ₉₊₁₄₊	14			9	14	8	1, 16
Rise Time (20 to 80%)	t ₉₊₁₅₋	15 14			9 11	15 14	8	1, 16
Nise IIIIle (20 to 80%)	t ₁₄₊ t ₁₅₊	14 15			11 11	14 15	8 8	1, 16 1, 16
Fall Time (20 to 80%)	t _{14–} t _{15–}	14 15			9 9	14 15	8 8	1, 16 1, 16
			1					1, 16

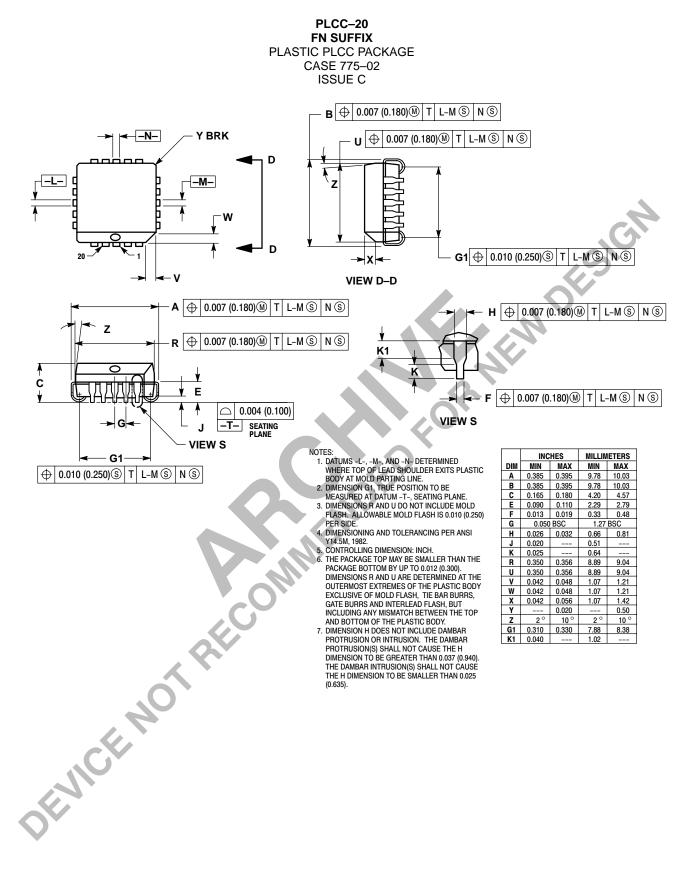
3. Reset all four flip-flops by applying pulse

V_{IHmax} V_{ILmin}

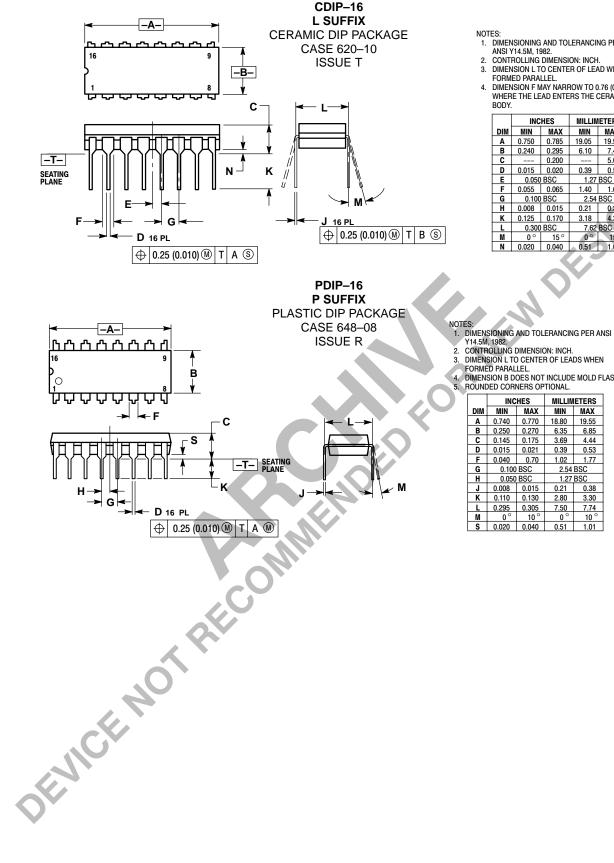
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to pin 9 prior to applying test voltage indicated.

PACKAGE DIMENSIONS



PACKAGE DIMENSIONS



NOTES:

DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
CONTROLLING DIMENSION: INCH.
DIMENSION L TO CENTER OF LEAD WHEN FOOMED DRAWLES

DIMENSION LTO CENTER OF LEAD WHEN FORMED PARALLEL.
DIMENSION F MAY NARROW TO 0.76 (0.030) WHERE THE LEAD ENTERS THE CERAMIC BODY.

	INC	HES	MILLIMETERS		
DIM	MIN	MAX	MIN	MAX	
Α	0.750	0.785	19.05	19.93	
В	0.240	0.295	6.10	7.49	
С		0.200		5.08	
D	0.015	0.020	0.39	0.50	
Е	0.050 BSC		1.27 BSC		
F	0.055	0.065	1.40	1.65	
G	0.100 BSC		2.54 BSC		
Н	0.008	0.015	0.21	0.38	
κ	0.125	0.170	3.18	4.31	
L	0.300 BSC		7.62	BSC	
М	0 °	15 °	0 °	15°	
Ν	0.020	0.040	0.51	1.01	

10

1.01

				R OF LEA	DS WHEN	
		ed Paral			E MOLD F	
		DED CORI				
		INC	HES	MILLIN	IETERS	
	DIM	MIN	MAX	MIN	MAX	
	Α	0.740	0.770	18.80	19.55	
	В	0.250	0.270	6.35	6.85	
	C	0.145	0.175	3.69	4.44	
	D	0.015	0.021	0.39	0.53	
	F	0.040	0.70	1.02	1.77	
	G	0.100	BSC	2.54	BSC	
	Н	0.050	BSC	1.27	BSC	
M	J	0.008	0.015	0.21	0.38	
	K	0.110	0.130	2.80	3.30	
	L	0.295	0.305	7.50	7.74	
	М	0°	10 °	0 °	10 °	

Notes

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